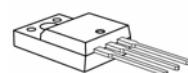
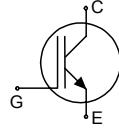
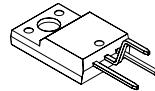


## HighSpeed 2-Technology

- Designed for:**
  - TV – Horizontal Line Deflection
- 2<sup>nd</sup> generation HighSpeed-Technology for 1200V applications offers:**
  - loss reduction in resonant circuits
  - temperature stable behavior
  - parallel switching capability
  - tight parameter distribution
  - $E_{off}$  optimized for  $I_C = 3A$
  - simple Gate-Control



P-TO220-3-31  
(FullPAK)



P-TO220-3-34  
(FullPAK)

- Complete product spectrum and PSpice Models : <http://www.infineon.com/igbt/>

Type	$V_{CE}$	$I_C$	$E_{off}$	$T_{j,max}$	Marking	Package	Ordering Code
IGA03N120H2	1200V	3A	0.15mJ	150°C	G03H1202	P-TO-220-3-31	Q67040-S4648
IGA03N120H2	1200V	3A	0.15mJ	150°C	G03H1202	P-TO-220-3-34	Q67040-S4654

## Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{CE}$	1200	V
Triangular collector peak current ( $V_{GS} = 15V$ )	$I_{Cpk}$		A
$T_C = 100^\circ\text{C}$ , $f = 32\text{kHz}$		8.2	
Pulsed collector current, $t_p$ limited by $T_{jmax}$	$I_{Cpuls}$	9	
Turn off safe operating area	-	9	
$V_{CE} \leq 1200V$ , $T_j \leq 150^\circ\text{C}$			
Gate-emitter voltage	$V_{GE}$	$\pm 20$	V
Power dissipation	$P_{tot}$	29	W
$T_C = 25^\circ\text{C}$			
Operating junction and storage temperature	$T_j$ , $T_{stg}$	-40...+150	°C
Soldering temperature, 1.6mm (0.063 in.) from case for 10s	-	260	

**Thermal Resistance**

Parameter	Symbol	Conditions	Max. Value	Unit
<b>Characteristic</b>				
IGBT thermal resistance, junction – case	$R_{thJC}$		4.3	K/W
Thermal resistance, junction – ambient	$R_{thJA}$	P-TO-220-3-31 P-TO-220-3-34	64	

**Electrical Characteristic, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified**

Parameter	Symbol	Conditions	Value			Unit
			min.	Typ.	max.	
<b>Static Characteristic</b>						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0\text{V}, I_C=300\mu\text{A}$	1200	-	-	V
Collector-emitter saturation voltage	$V_{CE(\text{sat})}$	$V_{GE} = 15\text{V}, I_C=3\text{A}$	-	2.2	2.8	
		$T_j=25^\circ\text{C}$	-	2.5	-	
		$T_j=150^\circ\text{C}$	-	2.4	-	
Gate-emitter threshold voltage	$V_{GE(\text{th})}$	$V_{GE} = 10\text{V}, I_C=3\text{A}, T_j=25^\circ\text{C}$	-	-	-	
		$I_C=90\mu\text{A}, V_{CE}=V_{GE}$	2.1	3	3.9	
		$V_{CE}=1200\text{V}, V_{GE}=0\text{V}$	-	-	-	
Zero gate voltage collector current	$I_{CES}$	$T_j=25^\circ\text{C}$	-	-	20	
		$T_j=150^\circ\text{C}$	-	-	80	
Gate-emitter leakage current	$I_{GES}$	$V_{CE}=0\text{V}, V_{GE}=20\text{V}$	-	-	100	nA
Transconductance	$g_{fs}$	$V_{CE}=20\text{V}, I_C=3\text{A}$	-	2	-	S

**Dynamic Characteristic**

Input capacitance	$C_{iss}$	$V_{CE}=25\text{V}$	-	205	-	pF
Output capacitance	$C_{oss}$	$V_{GE}=0\text{V}$	-	24	-	
Reverse transfer capacitance	$C_{rss}$	f=1MHz	-	7	-	
Gate charge	$Q_{\text{Gate}}$	$V_{CC}=960\text{V}, I_C=3\text{A}$	-	8.6	-	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	$L_E$	P-TO-220-3-31	-	7	-	nH

**Switching Characteristic, Inductive Load, at  $T_j=25\text{ }^\circ\text{C}$** 

Parameter	Symbol	Conditions	Value			Unit
			min.	Typ.	max.	
<b>IGBT Characteristic</b>						
Turn-on delay time	$t_{d(on)}$	$T_j=25\text{ }^\circ\text{C}$ $V_{CC}=800\text{V}, I_C=3\text{A}$ $V_{GE}=0\text{V}/15\text{V}$ $R_G=82\Omega$ $L_\sigma^{(1)}=180\text{nH}$ $C_\sigma^{(1)}=40\text{pF}$ Energy losses include "tail" and diode <sup>2)</sup> reverse recovery.	-	9.2	-	ns
Rise time	$t_r$		-	5.2	-	
Turn-off delay time	$t_{d(off)}$		-	281	-	
Fall time	$t_f$		-	29	-	
Turn-on energy	$E_{on}$		-	0.14	-	mJ
Turn-off energy	$E_{off}$		-	0.15	-	
Total switching energy	$E_{ts}$		-	0.29	-	

**Switching Characteristic, Inductive Load, at  $T_j=150\text{ }^\circ\text{C}$** 

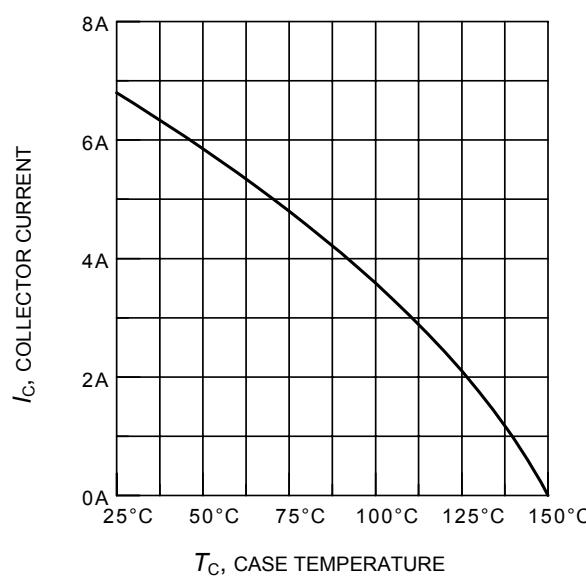
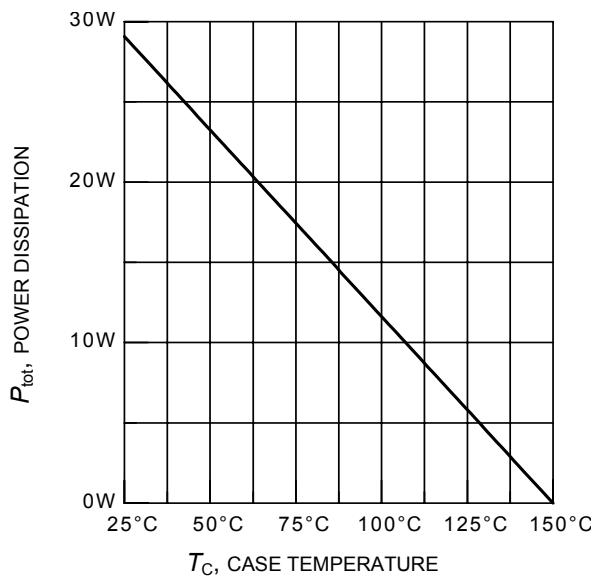
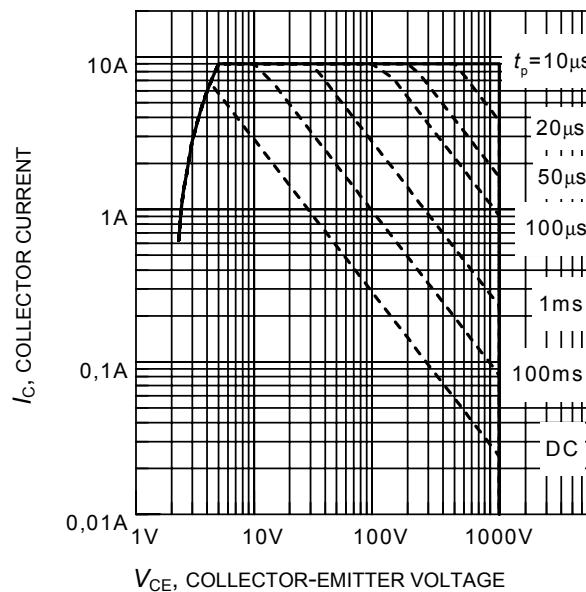
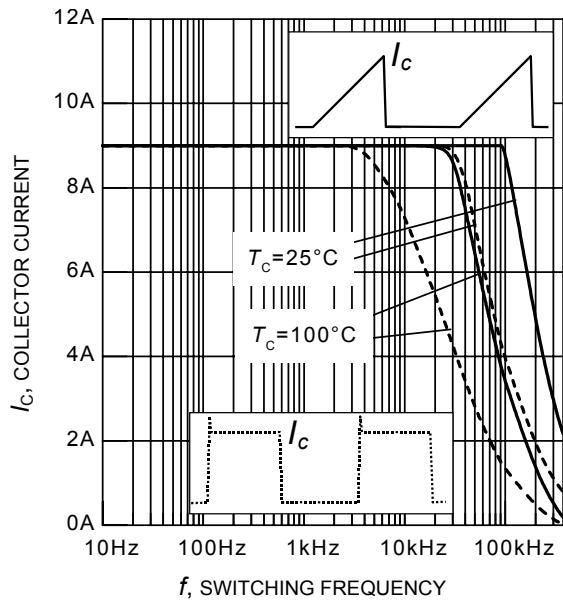
Parameter	Symbol	Conditions	Value			Unit
			min.	Typ.	max.	
<b>IGBT Characteristic</b>						
Turn-on delay time	$t_{d(on)}$	$T_j=150\text{ }^\circ\text{C}$ $V_{CC}=800\text{V}, I_C=3\text{A}$ $V_{GE}=0\text{V}/15\text{V}$ $R_G=82\Omega$ $L_\sigma^{(1)}=180\text{nH}$ $C_\sigma^{(1)}=40\text{pF}$ Energy losses include "tail" and diode <sup>2)</sup> reverse recovery.	-	9.4	-	ns
Rise time	$t_r$		-	6.7	-	
Turn-off delay time	$t_{d(off)}$		-	340	-	
Fall time	$t_f$		-	63	-	
Turn-on energy	$E_{on}$		-	0.22	-	mJ
Turn-off energy	$E_{off}$		-	0.26	-	
Total switching energy	$E_{ts}$		-	0.48	-	

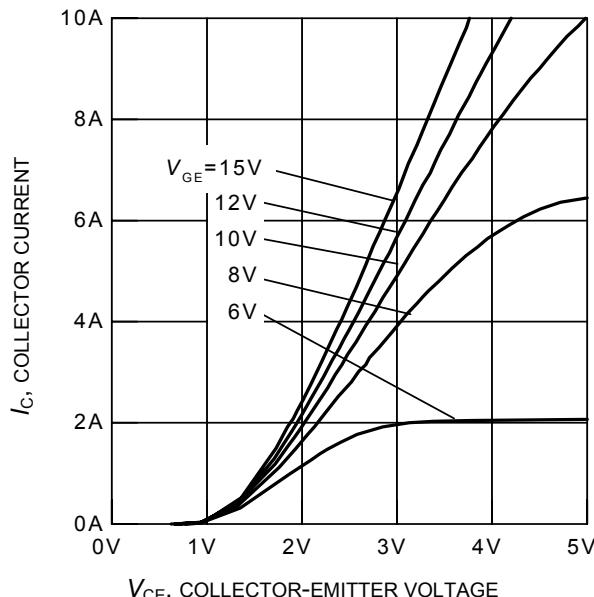
**Switching Energy ZVT, Inductive Load**

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>IGBT Characteristic</b>						
Turn-off energy	$E_{off}$	$V_{CC}=800\text{V}, I_C=3\text{A}$ $V_{GE}=0\text{V}/15\text{V}$ $R_G=82\Omega, C_r^{(1)}=4\text{nF}$ $T_j=25\text{ }^\circ\text{C}$ $T_j=150\text{ }^\circ\text{C}$	-	0.05	-	mJ
			-	0.09	-	

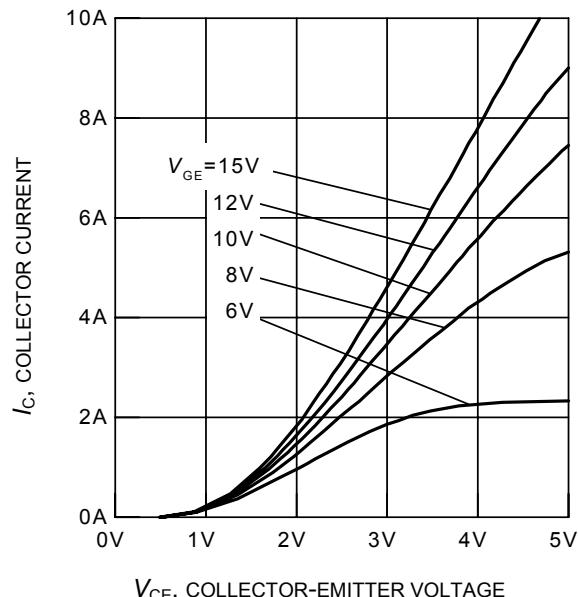
<sup>1)</sup> Leakage inductance  $L_\sigma$  and stray capacity  $C_\sigma$  due to dynamic test circuit in figure E

<sup>2)</sup> Commutation diode from device ICP03N120H2

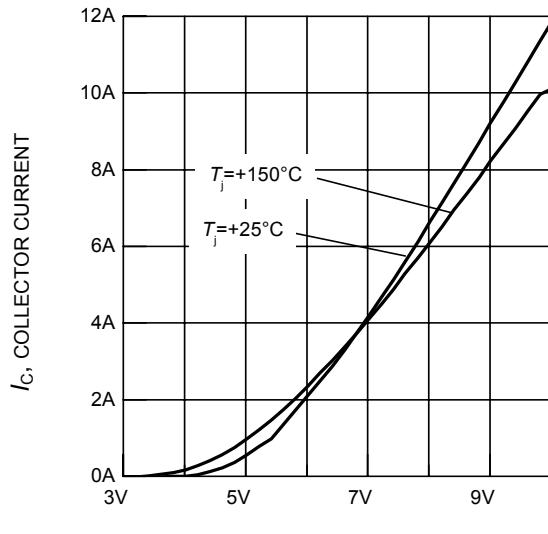




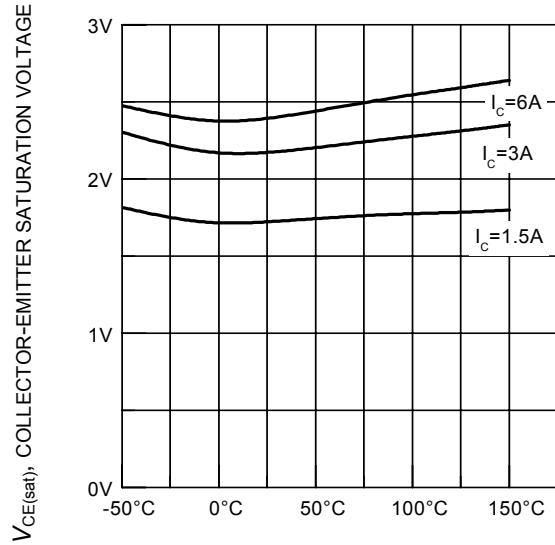
**Figure 5. Typical output characteristics**  
( $T_j = 25^\circ\text{C}$ )



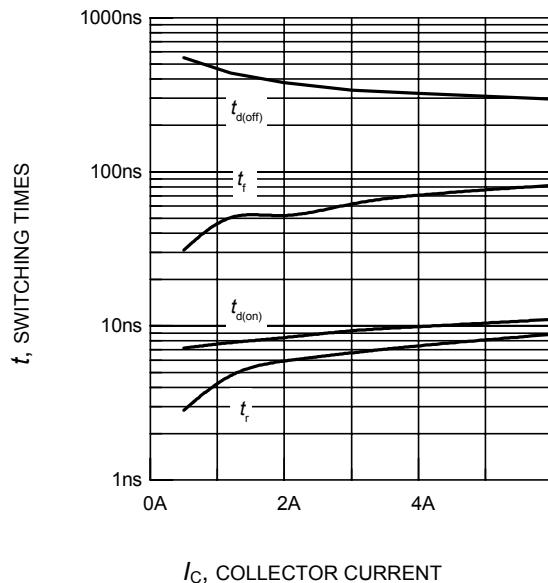
**Figure 6. Typical output characteristics**  
( $T_j = 150^\circ\text{C}$ )



**Figure 7. Typical transfer characteristics**  
( $V_{CE} = 20\text{V}$ )

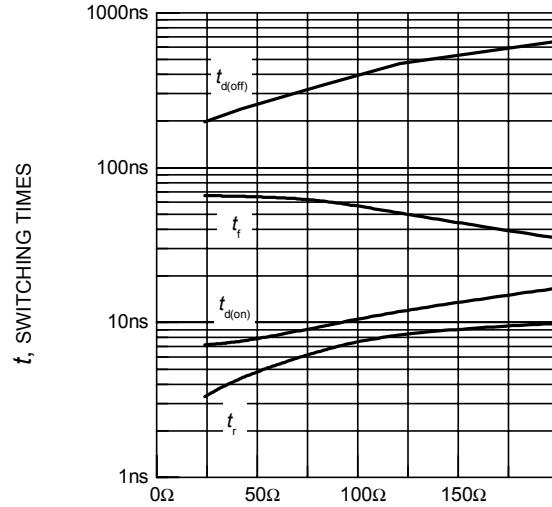


**Figure 8. Typical collector-emitter saturation voltage as a function of junction temperature**  
( $V_{GE} = 15\text{V}$ )



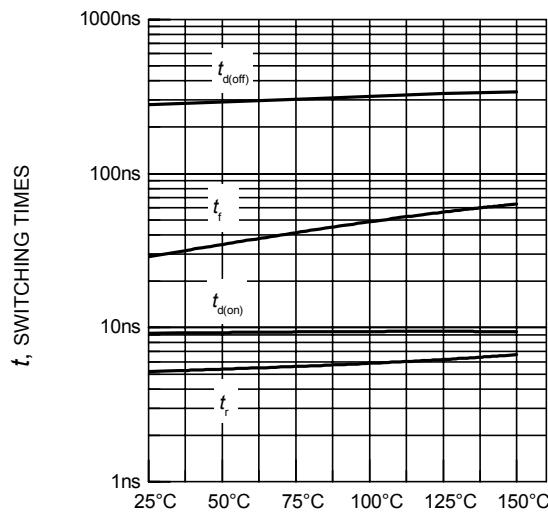
**Figure 9. Typical switching times as a function of collector current**

(inductive load,  $T_j = 150^\circ\text{C}$ ,  
 $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $R_G = 82\Omega$ ,  
dynamic test circuit in Fig.E)



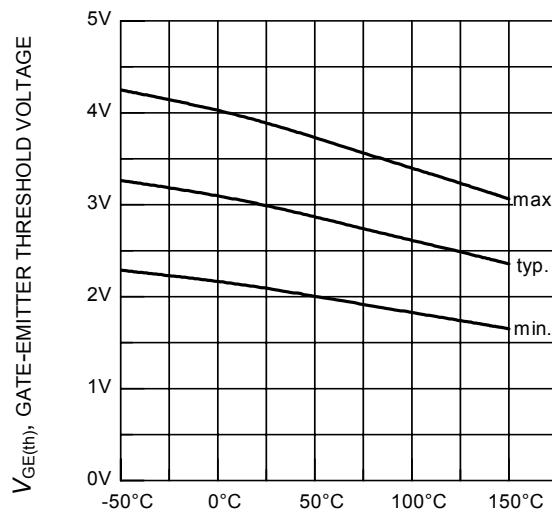
**Figure 10. Typical switching times as a function of gate resistor**

(inductive load,  $T_j = 150^\circ\text{C}$ ,  
 $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $I_C = 3\text{A}$ ,  
dynamic test circuit in Fig.E)



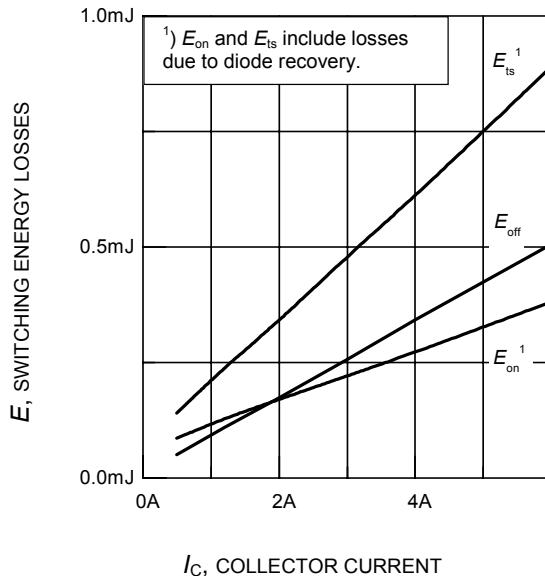
**Figure 11. Typical switching times as a function of junction temperature**

(inductive load,  $V_{CE} = 800\text{V}$ ,  
 $V_{GE} = +15\text{V}/0\text{V}$ ,  $I_C = 3\text{A}$ ,  $R_G = 82\Omega$ ,  
dynamic test circuit in Fig.E)

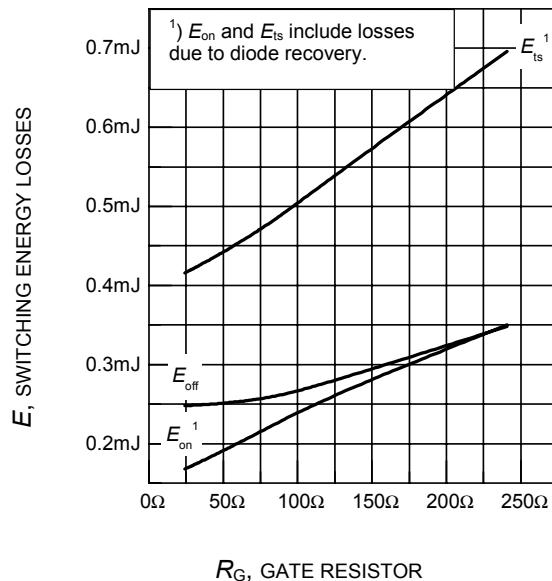


**Figure 12. Gate-emitter threshold voltage as a function of junction temperature**

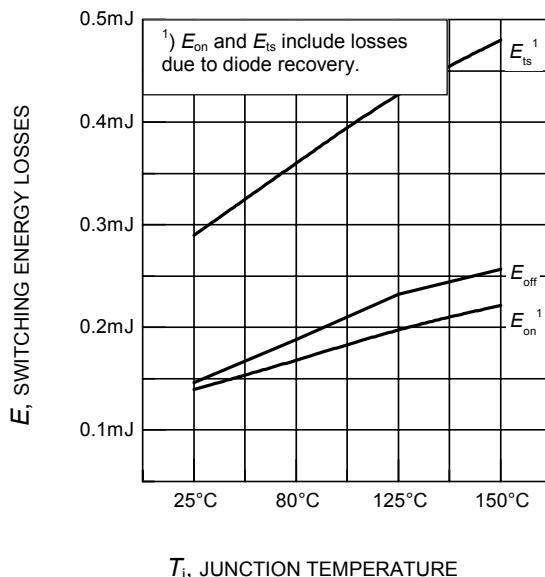
( $I_C = 0.09\text{mA}$ )



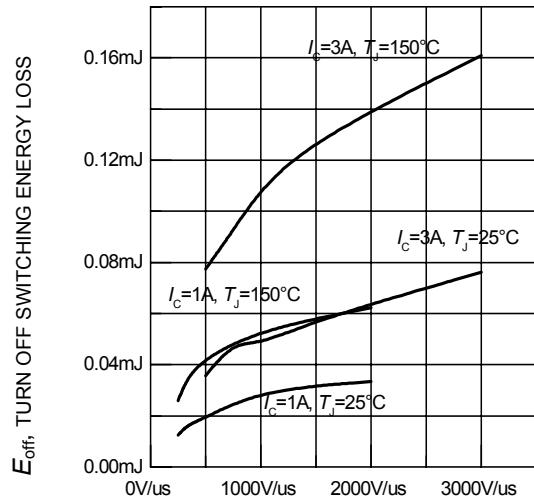
**Figure 13. Typical switching energy losses as a function of collector current**  
(inductive load,  $T_j = 150^\circ\text{C}$ ,  
 $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $R_G = 82\Omega$ ,  
dynamic test circuit in Fig.E )



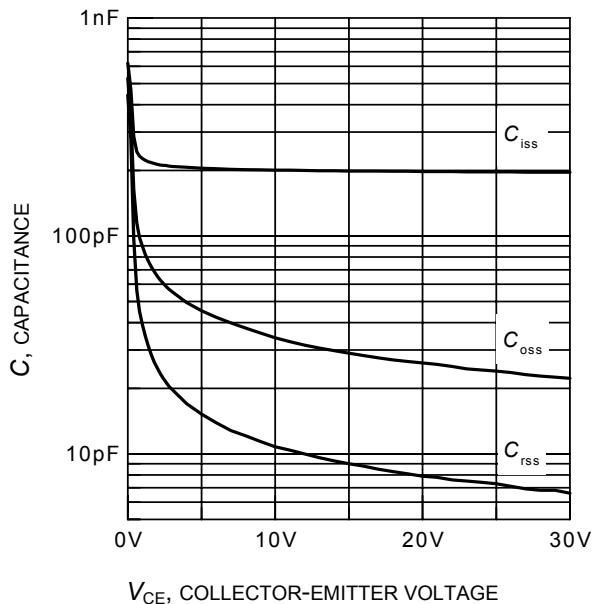
**Figure 14. Typical switching energy losses as a function of gate resistor**  
(inductive load,  $T_j = 150^\circ\text{C}$ ,  
 $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $I_C = 3\text{A}$ ,  
dynamic test circuit in Fig.E )



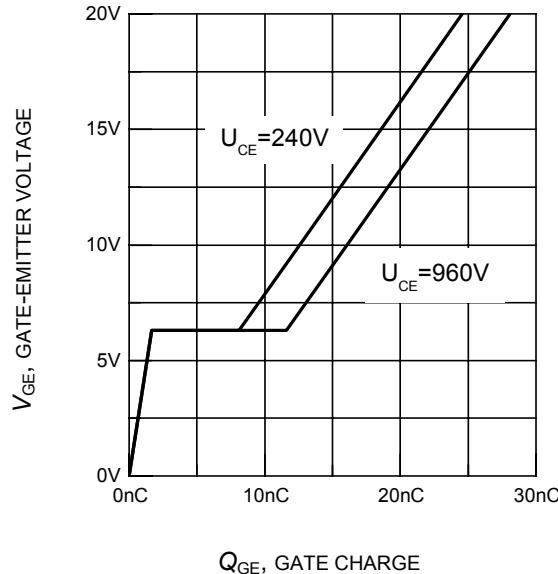
**Figure 15. Typical switching energy losses as a function of junction temperature**  
(inductive load,  $V_{CE} = 800\text{V}$ ,  
 $V_{GE} = +15\text{V}/0\text{V}$ ,  $I_C = 3\text{A}$ ,  $R_G = 82\Omega$ ,  
dynamic test circuit in Fig.E )



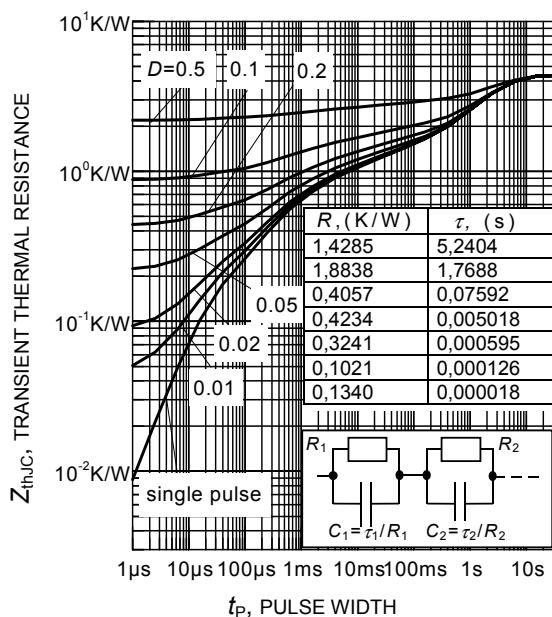
**Figure 16. Typical turn off switching energy loss for soft switching**  
(dynamic test circuit in Fig. E)



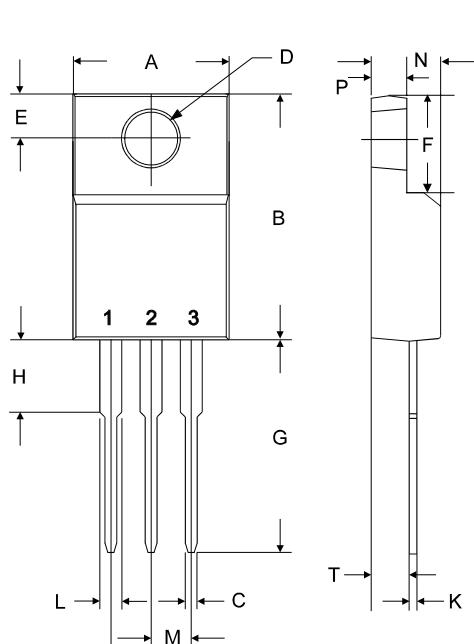
**Figure 19. Typical capacitance as a function of collector-emitter voltage**  
( $V_{GE} = 0V$ ,  $f = 1\text{MHz}$ )



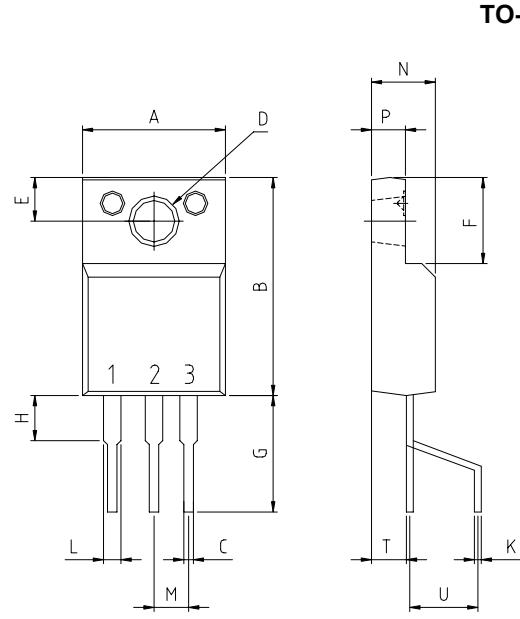
**Figure 18. Typical gate charge**  
( $I_C = 3\text{A}$ )



**Figure 17. IGBT transient thermal impedance as a function of pulse width**  
( $D = t_P/T$ )


**TO-220-3-31 (FullPAK)**

symbol	dimensions			
	[mm]		[inch]	
	min	max	min	max
A	10.37	10.63	0.4084	0.4184
B	15.86	16.12	0.6245	0.6345
C	0.65	0.78	0.0256	0.0306
D	2.95 typ.		0.1160 typ.	
E	3.15	3.25	0.124	0.128
F	6.05	6.56	0.2384	0.2584
G	13.47	13.73	0.5304	0.5404
H	3.18	3.43	0.125	0.135
K	0.45	0.63	0.0177	0.0247
L	1.23	1.36	0.0484	0.0534
M	2.54 typ.		0.100 typ.	
N	4.57	4.83	0.1800	0.1900
P	2.57	2.83	0.1013	0.1113
T	2.51	2.62	0.0990	0.1030


**TO-220-3-34 (FullPAK)**

symbol	dimensions			
	[mm]		[inch]	
	min	max	min	max
A	10.37	10.63	0.4084	0.4184
B	15.86	16.12	0.6245	0.6345
C	0.65	0.78	0.0256	0.0306
D	2.95 typ.		0.1160 typ.	
E	3.15	3.25	0.124	0.128
F	6.05	6.56	0.2384	0.2584
G	8.28	8.79	0.326	0.346
H	3.18	3.43	0.125	0.135
K	0.45	0.63	0.0177	0.0247
L	1.23	1.36	0.0484	0.0534
M	2.54 typ.		0.100 typ.	
N	4.57	4.83	0.1800	0.1900
P	2.57	2.83	0.1013	0.1113
T	2.51	2.62	0.0990	0.1030
U	5.00 typ.		0.197 typ.	

1: Gate

2: Collector

3: Emitter

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